

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/810,445	LEHE ET AL.	
Examiner	Art Unit	
Victor X. Nguyen	3734	

SEARCHED					
Class	Subclass	Date	Examiner		
606	159,191	10/5/2007	VN		
	198,200	ij	"		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventors searched	10/5/2007	VN		
Text/East searched	II	"		
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